



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No. 09/905,320
Filing Date July 13, 2001
Inventor Cem Basceri et al.
Assignee Micron Technology, Inc.
Group Art Unit 1762
Examiner Eric B. Fuller
Attorney's Docket No. MI22-1657
Title: Chemical Vapor Deposition Methods of Forming Barium Strontium Titanate
Comprising Dielectric Layers, Including Such Layers Having a Varied
Concentration of Barium and Strontium Within the Layer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

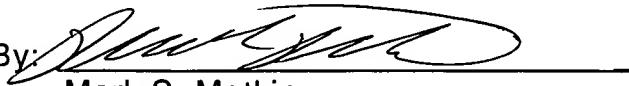
References - See Attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the cited art are attached hereto. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a request for continued examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 1-9-04

By: 
Mark S. Matkin
Reg. No. 32,268

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-1657		SERIAL NO. 09/905,320		
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT: MI22-1657				
					FILING DATE July 13, 2001		GROUP 1762		
U.S. PATENT DOCUMENTS									
*Examiner's Initials		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate	
	AA	6,602,376 B1	08/2003	Bradshaw		156	234		
	AB	6,527,028 B2	03/2003	Miller		156	555		
	AC	6,422,281 B1	07/2002	Ensign, Jr. et al.		156	495		
	AD	6,285,051 B1	09/2001	Ueda et al.		257	296		
	AE	6,236,076 B1	05/2001	Arita et al.		257	295		
	AF	5,635,741	06/1997	Tsu et al.		257	310		
	AG								
	AH								
	AJ								
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
	AJ							Yes	No
	AK								
	AL								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
	AM								
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